

NOV 03 2005

BEYER WEAVER & THOMAS, LLP

INTELLECTUAL PROPERTY LAW
500 12th Street, Suite 200, Oakland, CA 94607
Telephone: (510) 663-1100 Facsimile: (510) 663-0920
www.beyerlaw.com

FACSIMILE COVER SHEET

November 3, 2005

Receiver: Examiner Julio J. Maldonado
(USPTO Central Fax)

FAX #: (571) 273-8300

Sender: Denise S. Bergin
Our Ref. No.: NOVLP074

Application No: 09/998,993

Re: 1. Amendment Transmittal
2. Response F

Pages Including Cover Sheet(s): 11

MESSAGE:**RECEIVED**
OICE/IAP

NOV 04 2005

CONFIDENTIALITY NOTE

The information contained in this facsimile (FAX) message is legally privileged and confidential information intended only for the use of the receiver or firm named above. If the reader of this message is not the intended receiver, you are hereby notified that any dissemination, distribution or copying of this FAX is strictly prohibited. If you have received this FAX in error, please immediately notify the sender at the telephone number provided above and return the original message to the sender at the address above via the United States Postal Service. Thank you.

NOV. 3. 2005 11:40AM

5106630920

RECEIVED
CENTRAL FAX CENTER

NO. 311 P. 2

NOV 03 2005

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Turner, et al.

Application No.: 09/998,993

Filed: November 15, 2001

Title: PHOSPHOROUS-DOPED SILICON
DIOXIDE PROCESS TO CUSTOMIZE
CONTACT ETCH PROFILES

Attorney Docket No.:
NOVLP074/NVLS-000414

Examiner: Maldonado, Julio J.

Group: 2823

CERTIFICATE OF FACSIMILE TRANSMISSION

I hereby certify that this correspondence is being transmitted by facsimile to fax number 571-273-8300 to the U.S. Patent and Trademark Office on November 3, 2005.

Signed: 

Tara Hayden

RESPONSE F

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

This paper is submitted in response to the Office Action dated May 3, 2005 in the above-identified application. Please amend the application as follows:

Amendments to the Claims begin on page 2 of this paper.

Remarks/Arguments begin on page 8 of this paper.